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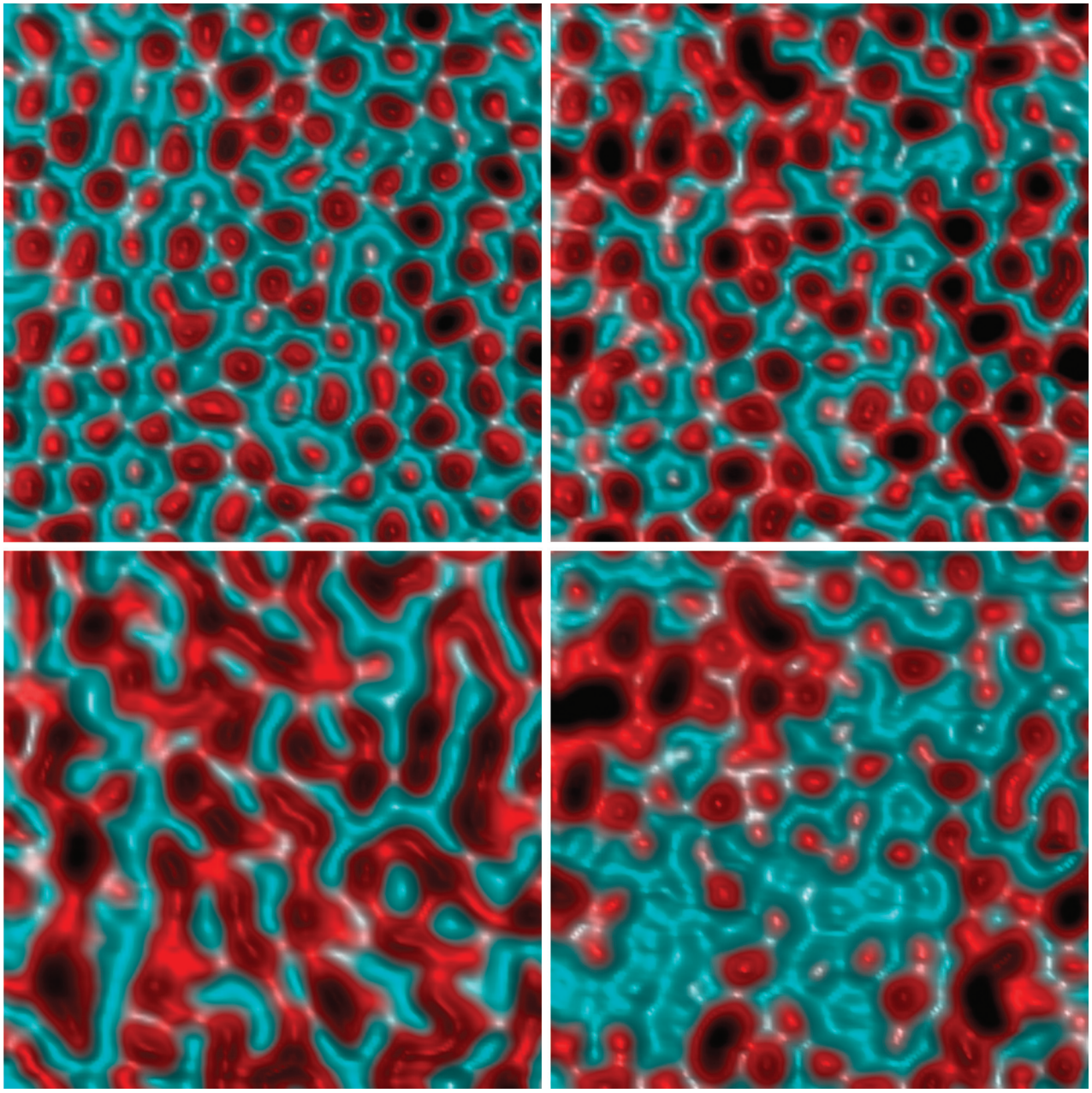
Microscopy TODAY



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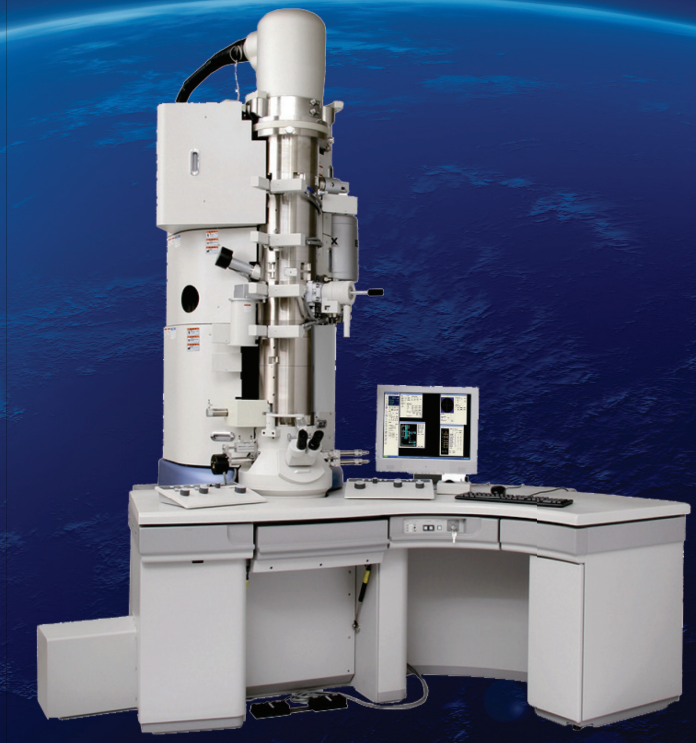
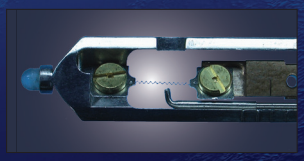
Total Solutions for In-Situ Environmental TEM

Hitachi's 300 kV Gas Environmental TEM (ETEM) Solutions
Three platforms to meet various levels of requirements

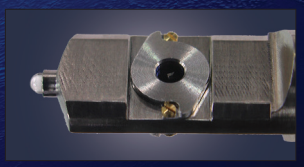
H-9500 Environmental TEM



HF-3300S Environmental TEM-STEM-SEM



Gas Injection-Heating Holder



Liquid Cell Holder

Hitachi is committed to providing a solution to every lab. For your 300 kV gas ETEM application, choose from the H-9500 Environmental TEM (100-300 kV, LaB_6), the HF-3300S Environmental TEM-STEM-SEM (80-300 kV, Cold FEG), or a customized Cs-corrected environmental TEM-STEM-SEM system with a large pole piece gap and sub-Å resolution.

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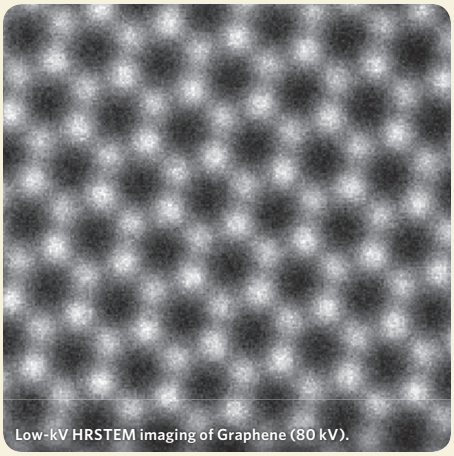
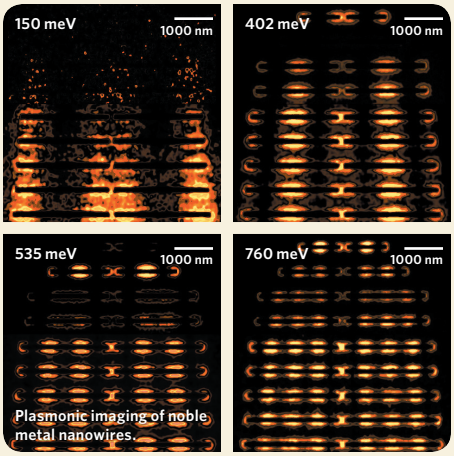
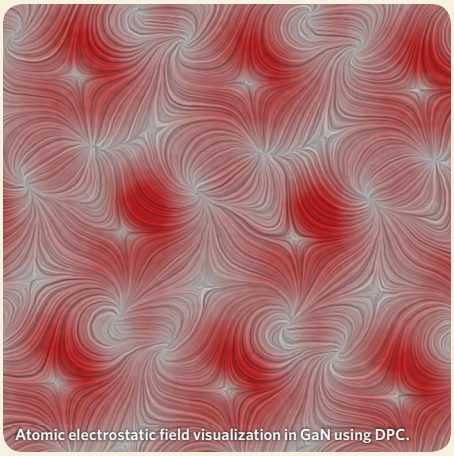
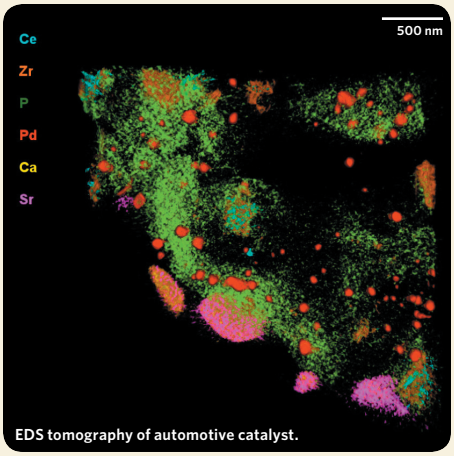

Low-kV HRSTEM imaging of Graphene (80 kV).

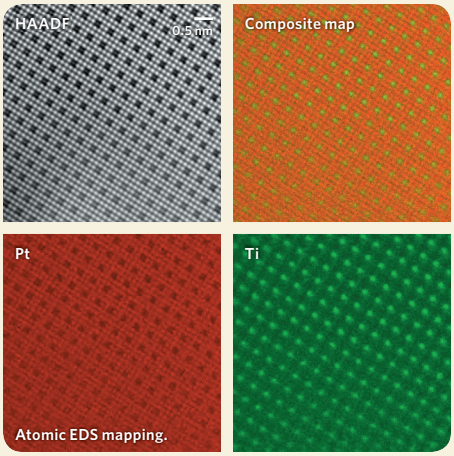


Plasmonic imaging of noble metal nanowires.

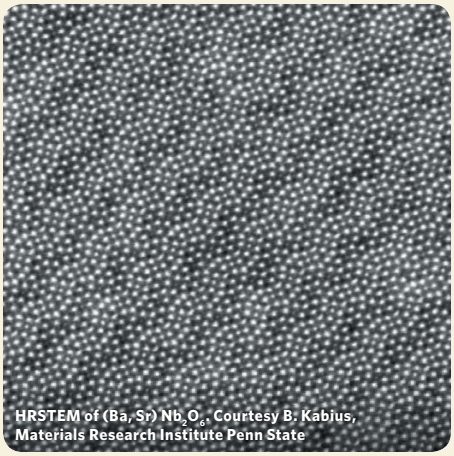

Atomic electrostatic field visualization in GaN using DPC.



EDS tomography of automotive catalyst.



Atomic EDS mapping.


HRSTEM of $(Ba,Sr)Nb_2O_6$. Courtesy B. Kabius, Materials Research Institute Penn State

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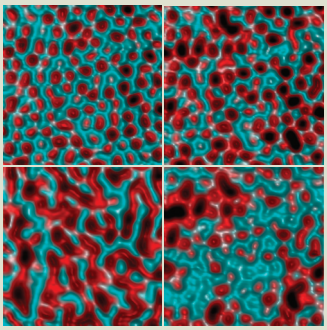

Coalescence of skyrmion-lattice phase into helimagnetic phase in $Fe_{0.5}Co_{0.5}Si$ with decreasing magnetic field. Clockwise from upper left: B = 15 mT, 5 mT, -15 mT, and -30 mT. Image width = 1.5 μm.

See article by Quacquarelli et al.

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